

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/714,759	TAKAHASHI ET AL.
	<b>Examiner</b> John T. Kwon	<b>Art Unit</b> 3747

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
all of the above		9/21/2006	JK